

Silicon N_Channel MOSFET Tetrode

- Short-channel transistor
 with high S / C quality factor
- For low-noise, gain-controlled input stage up to 1 GHz
- Pb-free (RoHS compliant) package 1)
- Qualified according AEC Q101





ESD (Electrostatic discharge) sensitive device, observe handling precaution!

Туре	Package	Pin Configuration					Marking	
BF998	SOT143	1=S	2=D	3=G2	4=G1	-	-	MOs
BF998R	SOT143R	1=D	2=S	3=G1	4=G2	-	-	MRs

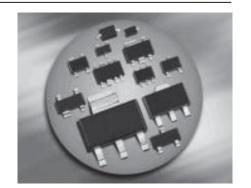
Maximum Ratings

Parameter	Symbol	Value	Unit
Drain-source voltage	V _{DS}	12	V
Continuous drain current	/ _D	30	mA
Gate 1/ gate 2-source current	±I _{G1/2SM}	10	
Total power dissipation	P _{tot}	200	
<i>T</i> _S ≤ 76 °C, BF998, BF998R			
Storage temperature	$T_{ m stg}$	-55 150	°C
Channel temperature	T_{ch}	150	

Thermal Resistance

Parameter	Symbol	Value	Unit
Channel - soldering point ²⁾ , BF998, BF998R	R _{thchs}	≤ 370	K/W

¹Pb-containing package may be available upon special request



²For calculation of R_{thJA} please refer to Application Note Thermal Resistance



Electrical Characteristics at T_A = 25°C, unless otherwise specified

Parameter	Symbol	Values			Unit
		min.	typ.	max.	
DC Characteristics			•	,	•
Drain-source breakdown voltage	V _{(BR)DS}	12	-	-	V
$I_{\rm D}$ = 10 $\mu {\rm A}, \ V_{\rm G1S}$ = -4 V, $V_{\rm G2S}$ = -4 V					
Gate 1 source breakdown voltage	±V _{(BR)G1SS}	8	-	12	
$\pm I_{G2S} = 10 \text{ mA}, \ V_{G2S} = V_{DS} = 0$					
Gate2 source breakdown voltage	±V _{(BR)G2SS}	8	-	12	
$\pm I_{G2S} = 10 \text{ mA}, \ V_{G2S} = V_{DS} = 0$					
Gate 1 source leakage current	±I _{G1SS}	-	-	50	nA
$\pm V_{G1S} = 5 \text{ V}, \ V_{G2S} = V_{DS} = 0$					
Gate 2 source leakage current	±I _{G2SS}	-	-	50	nA
$\pm V_{G2S} = 5 \text{ V}, \ V_{G2S} = V_{DS} = 0$					
Drain current	I _{DSS}	5	9	15	mA
$V_{\rm DS}$ = 8 V, $V_{\rm G1S}$ = 0 , $V_{\rm G2S}$ = 4 V					
Gate 1 source pinch-off voltage	-V _{G1S(p)}	-	0.8	2.5	V
$V_{\rm DS}$ = 8 V, $V_{\rm G2S}$ = 4 V, $I_{\rm D}$ = 20 $\mu {\rm A}$					
Gate 2 source pinch-off voltage	-V _{G2S(p)}	-	0.8	2	
$V_{\rm DS}$ = 8 V, $V_{\rm G1S}$ = 0 , $I_{\rm D}$ = 20 μA	(, ,				



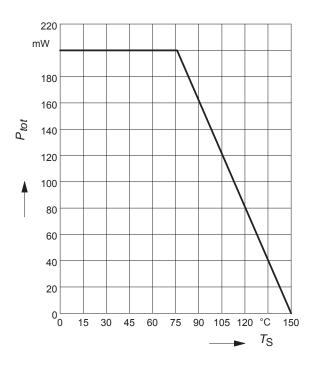
Electrical Characteristics at T_{Δ} = 25°C, unless otherwise specified

Parameter	Symbol	Values			Unit
		min.	typ.	max.	
AC Characteristics (verified by random sar	mpling)				
Forward transconductance	g_{fs}	20	24	-	-
$V_{\rm DS}$ = 8 V, $I_{\rm D}$ = 10 mA, $V_{\rm G2S}$ = 4 V					
Gate1 input capacitance	C_{g1ss}	-	2.1	2.5	pF
$V_{\rm DS}$ = 8 V, $I_{\rm D}$ = 10 mA, $V_{\rm G2S}$ = 4 V,					
f = 10 MHz					
Gate 2 input capacitance	$C_{\rm g2ss}$	-	1.2	-	pF
$V_{\rm DS}$ = 8 V, $I_{\rm D}$ = 10 mA, $V_{\rm G2S}$ = 4 V,					
f = 10 MHz					
Feedback capacitance	C _{dg1}	-	25	-	fF
V_{DS} = 8 V, I_{D} = 10 mA, V_{G2S} = 4 V,					
f = 10 MHz					
Output capacitance	C_{dss}	-	1.1	-	pF
$V_{\rm DS}$ = 8 V, $I_{\rm D}$ = 10 mA, $V_{\rm G2S}$ = 4 V,					
f = 10 MHz					
Power gain	G_{p}				dB
$V_{\rm DS}$ = 8 V, $I_{\rm D}$ = 10 mA, $V_{\rm G2S}$ = 4 V,					
f = 45 MHz		-	28	-	
$V_{\rm DS}$ = 8 V, $I_{\rm D}$ = 10 mA, $V_{\rm G2S}$ = 4 V,					
f = 800 MHz		-	20	-	
Noise figure	F				dB
$V_{\rm DS}$ = 8 V, $I_{\rm D}$ = 10 mA, $V_{\rm G2S}$ = 4 V,					
f = 45 MHz		-	2.8	-	
$V_{\rm DS}$ = 8 V, $I_{\rm D}$ = 10 mA, $V_{\rm G2S}$ = 4 V,					
f = 800 MHz		-	1.8	-	
Gain control range	ΔG_{p}	40	50	-	
V_{DS} = 8 V, V_{G2S} = 42 V, f = 800 MHz					



Total power dissipation $P_{tot} = f(T_S)$

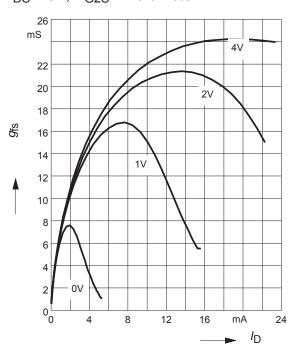
BF998, BF998R



Gate 1 forward transconductance

 $g_{fs} = f(I_D)$

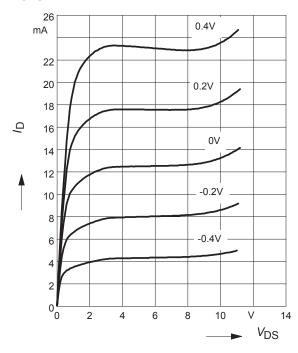
 V_{DS} = 5V, V_{G2S} = Parameter



Output characteristics $I_D = f(V_{DS})$

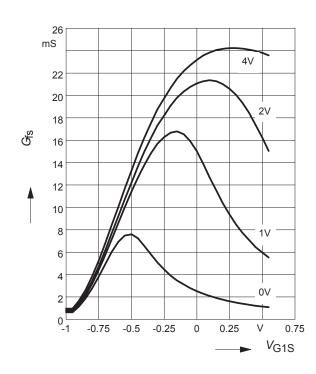
 $V_{\rm G2S} = 4 \text{ V}$

 V_{G1S} = Parameter



Gate 1 forward transconductance

$$g_{fs1} = f(V_{G1S})$$

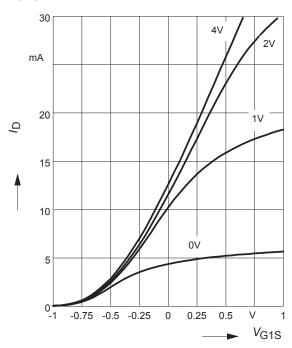




Drain current $I_D = f(V_{G1S})$

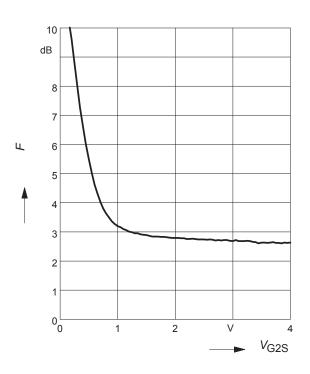
 $V_{\rm DS} = 5V$

 $V_{\rm G2S}$ = Parameter



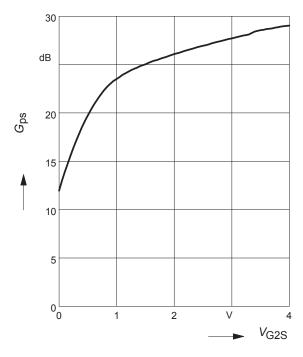
Noise figure $F = f(V_{G2S})$

f = 45 MHz



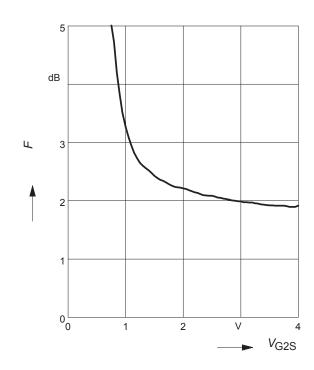
Power gain $G_{ps} = f(V_{G2S})$

f = 45 MHz



Noise figure $F = f(V_{G2S})$

f = 800 MHz

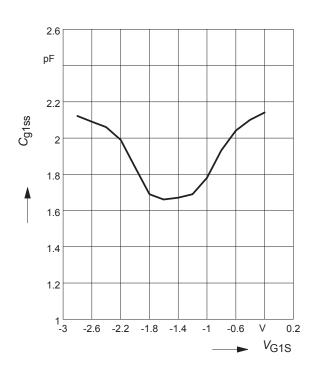




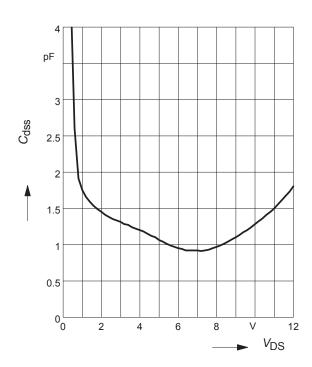
Power gain $G_{pS} = f(V_{G2S})$ f = 800 MHz

gg 10 5 0 -10 0 1 2 V 4

Gate 1 input capacitance $C_{g1ss} = f(V_{G1S})$



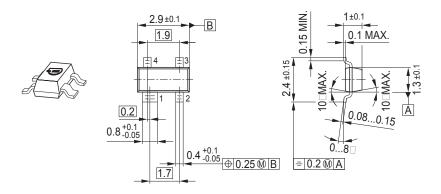
Output capacitance $C_{dss} = f(V_{DS})$



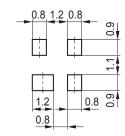
6



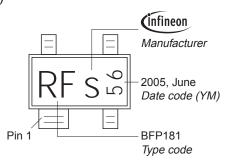
Package Outline



Foot Print

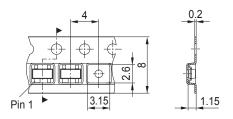


Marking Layout (Example)



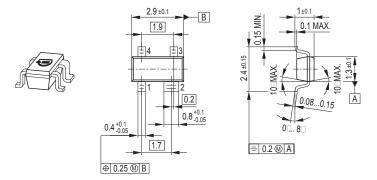
Standard Packing

Reel ø180 mm = 3.000 Pieces/Reel Reel ø330 mm = 10.000 Pieces/Reel

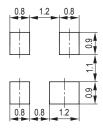




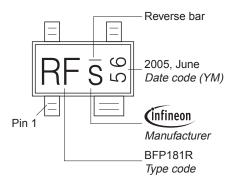
Package Outline



Foot Print

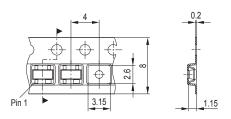


Marking Layout (Example)



Standard Packing

Reel ø180 mm = 3.000 Pieces/Reel Reel ø330 mm = 10.000 Pieces/Reel





Edition 2006-02-01 Published by Infineon Technologies AG 81726 München, Germany © Infineon Technologies AG 2007. All Rights Reserved.

Attention please!

The information given in this dokument shall in no event be regarded as a guarantee of conditions or characteristics ("Beschaffenheitsgarantie"). With respect to any examples or hints given herein, any typical values stated herein and/or any information regarding the application of the device, Infineon Technologies hereby disclaims any and all warranties and liabilities of any kind, including without limitation warranties of non-infringement of intellectual property rights of any third party.

Information

For further information on technology, delivery terms and conditions and prices please contact your nearest Infineon Technologies Office (www.infineon.com).

Warnings

Due to technical requirements components may contain dangerous substances. For information on the types in question please contact your nearest Infineon Technologies Office.

Infineon Technologies Components may only be used in life-support devices or systems with the express written approval of Infineon Technologies, if a failure of such components can reasonably be expected to cause the failure of that life-support device or system, or to affect the safety or effectiveness of that device or system.

Life support devices or systems are intended to be implanted in the human body, or to support and/or maintain and sustain and/or protect human life. If they fail, it is reasonable to assume that the health of the user or other persons may be endangered.

9 2007-04-20